



SHEET 1 OF 1

INFORMATION DISCLOSURE  
CITATION IN AN  
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APPLICANT  
Yutaka HIROSE, et al.

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## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code(s) (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
TJ		US 6,057,564	05/02/2000	Rennle	
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
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## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes - Number - Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
TJ		JP 11-54788	02/26/1999	TOSHIBA CORP.		JAPAN (w/English Abstract)	
TJ		JP 10-223901	08/21/1998	SONY CORP.		JAPAN (w/English Abstract)	
TJ		JP 2000-150792	05/30/2000	AGENCY OF IND SCIENCE & TECHNOL		JAPAN (w/English Abstract)	

## OTHER ART (including Author, Title, Date, Patent No., Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
TJ		HASHIZUME, T., et al. "Characterization of GaN and AlGaN Surfaces and Their Insulated Gate Structures." The Institute of Electronics, Information and Communication Engineers. Technical Report of IEICE., ED2002-87, LQE2002-62 (2002-08). Pp. 57-60, June 14, 2002.
TJ		KUSUNOKI, S., et al. "Hot-Carrier-Resistant Structure by Re-oxidized Nitrided Oxide Sidewall for Highly Reliable and High Performance LDD MOSFETS.", IEEE, IEDM 01, 25.4.1- 25.4.4, pp. 349-352, 1991

EXAMINER

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